Inventor: Cobbley et al. Docket No.: 2269-3437.9US

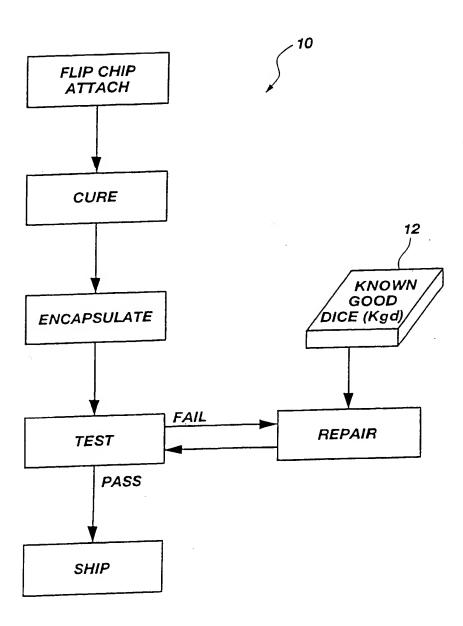


Fig. 1 (PRIOR ART)

Inventor: Cobbley et al. Docket No.: 2269-3437.9US

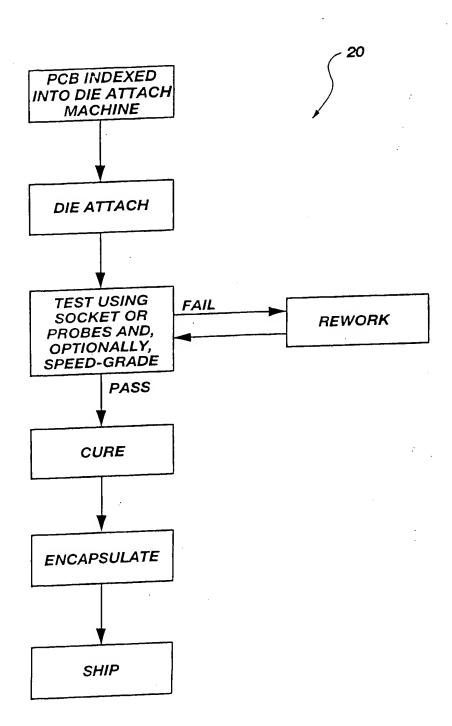


Fig. 2

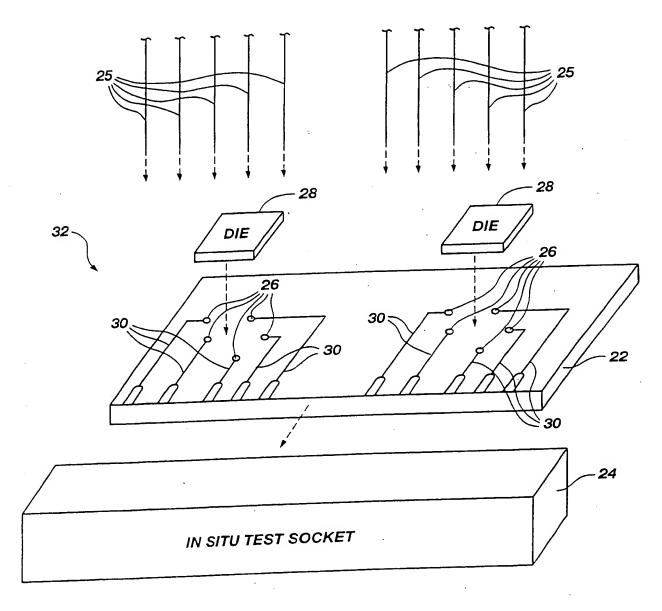


Fig. 3

Inventor; Cobbley et al. Docket No.: 2269-3437.9US

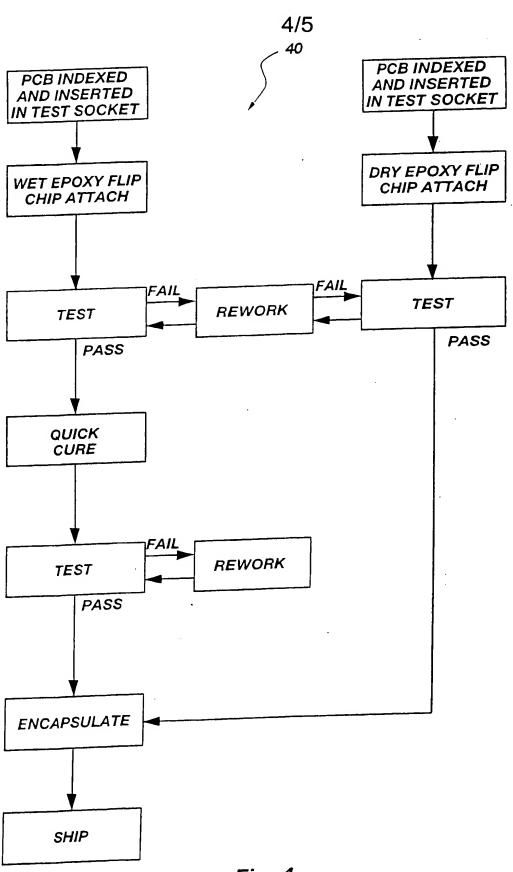


Fig. 4

TITLE: METHOD FOR IN-LINE TESTING OF FLIP-CHIP SEMICONDUCTOR ASSEMBLIES Inventor: Cobbley et al. Docket No.: 2269-3437.9US

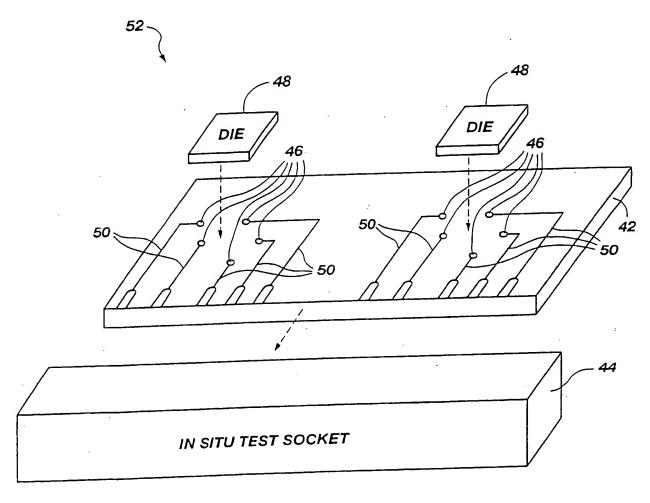


Fig. 5